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CONFIRMATION NO. 8779

SERIAL NUMBER 03/03/01,511	FILING DATE 08/27/2001 RULE	CLASS 439	GROUP ART UNIT 3812	ATTORNEY DOCKET NO. 010319
<b>APPLICANTS</b> Mamoru Nakasugi, Kanagawa, JAPAN; Nobuharu Noji, Kanagawa, JAPAN; Tetsu Saito, Kanagawa, JAPAN; Masahiro Hatakeyama, Kanagawa, JAPAN; Toshihumi Kimba, Kanagawa, JAPAN; Kiyoshi Saito, Kanagawa, JAPAN; Shoji Yoshikawa, Tokyo, JAPAN; Takashi Murakami, Tokyo, JAPAN; Kenji Wakasaka, Kanagawa, JAPAN; Tsutomu Kakinaka, Kanagawa, JAPAN; Shin Otsuda, Kanagawa, JAPAN; Munehiro Saito, Kanagawa, JAPAN; Yoshio Yamazaki, Tokyo, JAPAN; Takamitsu Nagai, Kanagawa, JAPAN; Ichiro Nagahama, Kanagawa, JAPAN;				
<b>CONTINUING DATA</b> <i>none</i>				
<b>FOREIGN APPLICATIONS</b> JAPAN 2000-183104 08/27/2000 JAPAN 2000-228101 07/28/2000 JAPAN 2000-335834 11/02/2000 JAPAN 2001-11218 01/18/2001 JAPAN 2001-31901 02/08/2001 JAPAN 2001-31808 02/08/2001 JAPAN 2001-33589 02/08/2001 JAPAN 2001-35089 02/13/2001 JAPAN 2001-158882 05/28/2001 JAPAN 2001-182041 05/10/2001 JAPAN 2001-189304 08/22/2001				
IF REQUIRED, FOREIGN FILING LICENSE GRANTED 08/28/2001				
Foreign Priority Claims 35 USC 119 (a)-(d) conditions met 35 USC 119 (e) conditions met Addressed and Acknowledged ADDRESS 33859	<input checked="" type="checkbox"/> 1a <input type="checkbox"/> 1b <input type="checkbox"/> 1c <input type="checkbox"/> 1d <input type="checkbox"/> 1e <input type="checkbox"/> 1f <input type="checkbox"/> 1g <input type="checkbox"/> 1h <input type="checkbox"/> 1i Addressed and Acknowledged ADDRESS 33859	STATE OR COUNTRY JAPAN	SHEETS DRAWING 30	TOTAL CLAIMS 60
INDEPENDENT CLAIMS 13				
TITLE Inspection system by charged particle beam and method of manufacturing devices using the system				

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